

## FOR IMMEDIATE RELEASE

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## **NanoLab Technologies Selects SEMICAPS Scanning Optical Microscope for Advanced Optical Fault Localization Services**

***New failure analysis system enhances NanoLab and Presto Engineering's ability to provide turn-key outsourced product engineering capabilities to chip manufacturers***

SAN JOSE, CALIF., November 5, 2007—SEMICAPS Pte Ltd, a leading supplier of semiconductor failure analysis systems, announced today that NanoLab Technologies, Inc. has purchased the SEMICAPS SOM 4000 Scanning Optical Microscope System for advanced optical fault localization. SEMICAPS will showcase its suite of failure analysis solutions at booth 118 during ISTFA 2007, taking place November 4-8, at the San Jose McEnergy Convention Center, San Jose, Calif.

The SEMICAPS SOM 4000 is an inverted scanning optical microscope system that can be used in a stand-alone analytical configuration or docked to an automated tester. It is the industry's most advanced global fault isolation tool designed to meet the demanding requirements of design debug, product engineering, yield enhancement and failure analysis applications. NanoLab Technologies, located in Sunnyvale, Calif., will use the system as part of its suite of analytical services for semiconductor manufacturers. NanoLab recently entered into an agreement with Presto Engineering, Inc., San Jose, Calif., to provide manufacturers with turn-key test and design success analysis services, helping them to improve the speed and efficiency and minimize the cost of bringing new products to market.

“During product engineering, fault isolation is a major bottleneck in analyzing defects from designs below 130nm. Near infra-red technologies are now the only efficient way to physically localize these defects by imaging through the device substrate,” said Michel Villemain, Presto Engineering CEO. “I am very happy that our partnership with NanoLab Technologies brings a

capability like the SOM 4000 to our mutual customers.”

Adds Jacob Phang, Executive Chairman, SEMICAPS, Pte Ltd. “The SOM 4000 enables our customers to find defects in new designs faster. The unit can then be wheeled onto the test floor for docking with any production test system for tester-based analysis.”

“We carefully evaluated the capabilities of the SOM 4000 and concluded that the features, performance and configuration more than satisfied our failure analysis requirements, in addition to supporting the direct dock capability that was required by our technology development partner, Presto Engineering,” said NanoLab Technologies President and CEO, John Traub. “Our customers have been impressed with the results from the SOM 4000, and are exploring means to exploit the breadth of product engineering capabilities that are offered through NanoLabs’ partnership with Presto Engineering.”

Comprised of a portable base unit and a probe station module, the SOM 4000 system has the flexibility for use with full 12-inch wafers, wafer parts or package devices for frontside and backside analysis. In analytical mode, the base unit is docked to the probe station module for wafer, wafer part and package analysis. In tester-docked mode, the base unit can be wheeled onto the test floor for docking with any production tester for tester-based analysis. A proprietary power alteration technique, incorporating voltage bias, voltage change detection and pulsing, achieves the highest available detection sensitivity, while the flexible, high-resolution laser scanning module provides the shortest setup time for tester-based analysis.

Note to editor: A photo of the SOM 4000 system is available.

#### **ABOUT SEMICAPS PTE LTD**

SEMICAPS, located in Singapore, is a comprehensive provider of equipment and services to semiconductor failure analysis customers world-wide through excellence in innovation and quality in service. SEMICAPS’ main products include the Scanning Optical Microscope System (SOM) for the active localization of integrated circuit defects using power alteration and tested-based techniques, and the Photon Emission Microscope (PEM) for the passive localization of integrated circuit defects using panchromatic imaging and spectroscopy. Additional information is available on the company’s website at [www.semicaps.com](http://www.semicaps.com).

Information about NanoLab Technologies, Inc. can be found at [www.nanolabtechnologies.com](http://www.nanolabtechnologies.com).

Information about Presto Engineering, Inc. can be found at [www.presto-eng.com](http://www.presto-eng.com).

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